

# STD90NH02L

# N-CHANNEL 24V - 0.0052 Ω - 60A DPAK/IPAK STripFET<sup>TM</sup> III POWER MOSFET

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STD90NH02L	24 V	< 0.006 Ω	60 A(2)

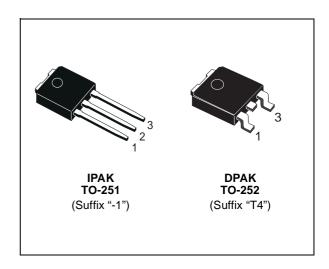
- TYPICAL  $R_{DS}(on) = 0.0052 \Omega @ 10 V$
- TYPICAL R<sub>DS</sub>(on) =  $0.007 \Omega @ 5 V$
- R<sub>DS(ON)</sub> \* Qg INDUSTRY's BENCHMARK
- CONDUCTION LOSSES REDUCED
- SWITCHING LOSSES REDUCED
- LOW THRESHOLD DEVICE
- THROUGH-HOLE IPAK (TO-251) POWER PACKAGE IN TUBE (SUFFIX "-1")
- SURFACE-MOUNTING DPAK (TO-252) POWER PACKAGE IN TAPE & REEL (SUFFIX "T4")

### **DESCRIPTION**

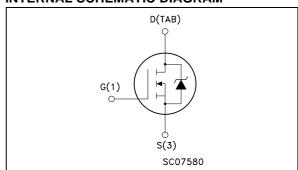
The **STD90NH02L** utilizes the latest advanced design rules of ST's proprietary STripFET<sup>™</sup> technology. This is suitable fot the most demanding DC-DC converter application where high efficiency is to be achieved.

### **APPLICATIONS**

 SPECIFICALLY DESIGNED AND OPTIMISED FOR HIGH EFFICIENCY DC/DC CONVERTES



### **INTERNAL SCHEMATIC DIAGRAM**



### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>spike(1)</sub>	Drain-source Voltage Rating	30	V
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	24	V
$V_{DGR}$	Drain-gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	24	V
V <sub>GS</sub>	Gate- source Voltage	± 20	V
I <sub>D</sub> (2)	Drain Current (continuous) at T <sub>C</sub> = 25°C	60	А
I <sub>D</sub> (2)	Drain Current (continuous) at T <sub>C</sub> = 100°C	60	А
I <sub>DM</sub> (3)	Drain Current (pulsed)	240	Α
P <sub>tot</sub>	Total Dissipation at T <sub>C</sub> = 25°C	95	W
	Derating Factor	0.63	W/°C
E <sub>AS</sub> (4)	Single Pulse Avalanche Energy	600	mJ
T <sub>stg</sub>	Storage Temperature	-55 to 175	°C
Tj	Max. Operating Junction Temperature	-55 to 175	

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### THERMAL DATA

Rthj-case	Thermal Resistance Junction-case	Max	1.58	°C/W
Rthj-amb	Thermal Resistance Junction-ambient	Max	100	°C/W
T <sub>I</sub>	Maximum Lead Temperature For Soldering Purpose		275	°C

# **ELECTRICAL CHARACTERISTICS** ( $T_{CASE} = 25~^{\circ}C$ UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 25 \text{ mA}, V_{GS} = 0$	24			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 20 V V <sub>DS</sub> = 20 V T <sub>C</sub> = 125°C			1 10	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20V			±100	nA

### ON (5)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$	$I_D = 250 \mu A$	1	1.8	2.5	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10 V V <sub>GS</sub> = 5 V	I <sub>D</sub> = 30 A I <sub>D</sub> = 15 A		0.0052 0.007	0.006 0.011	Ω Ω

### **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (5)	Forward Transconductance	V <sub>DS</sub> = 10 V I <sub>D</sub> = 30 A		40		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 15V f = 1 MHz V_{GS} = 0$		2850 800 120		pF pF pF
R <sub>G</sub>	Gate Input Resistance	f = 1 MHz Gate DC Bias = 0 Test Signal Level = 20 mV Open Drain		1		Ω

### **ELECTRICAL CHARACTERISTICS** (continued)

### **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on Delay Time Rise Time	$\begin{aligned} V_{DD} &= 10 \text{ V} & I_D &= 30 \text{ A} \\ R_G &= 4.7 \Omega & V_{GS} &= 10 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{aligned}$		13 75		ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Source Gate Charge Gate-Drain Charge	V <sub>DD</sub> = 10 V I <sub>D</sub> = 60 A V <sub>GS</sub> = 10 V		47.5 10 7	64	nC nC nC
Q <sub>oss</sub> (6)	Output Charge	V <sub>DS</sub> = 16 V V <sub>GS</sub> = 0 V		18.8		nC
Q <sub>gls</sub> (7)	Third-quadrant Gate Charge	V <sub>DS</sub> < 0 V V <sub>GS</sub> = 10 V		44		nC

### **SWITCHING OFF**

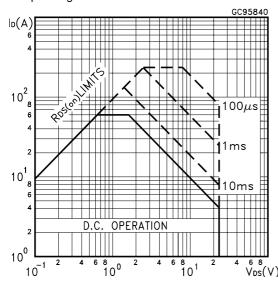
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(off)</sub>	Turn-off Delay Time Fall Time	$\begin{split} V_{DD} &= 10 \text{ V} & I_D = 30 \text{ A} \\ R_G &= 4.7 \Omega, & V_{GS} = 10 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{split}$		50 18	24.3	ns ns

### **SOURCE DRAIN DIODE**

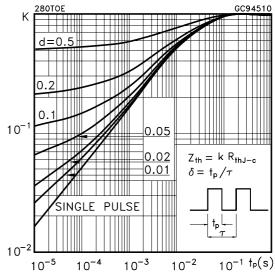
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub>	Source-drain Current Source-drain Current (pulsed)				60 240	A A
V <sub>SD</sub> (5)	Forward On Voltage	I <sub>SD</sub> = 30 A V <sub>GS</sub> = 0			1.3	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 60 \text{ A}$ di/dt = $100 \text{A}/\mu \text{s}$ $V_{DD} = 16 \text{ V}$ $T_j = 150 ^{\circ} \text{C}$ (see test circuit, Figure 5)		35 35 2	47 47	ns nC A

<sup>(1)</sup> Garanted when external Rg=4.7  $\Omega$  and  $t_f < t_{fmax}$ . (2) Value limited by wire bonding (3) Pulse width limited by safe operating area. (4) Starting  $T_j = 25$  °C,  $I_D = 30$ Å,  $V_{DD} = 15$ V

### Safe Operating Area

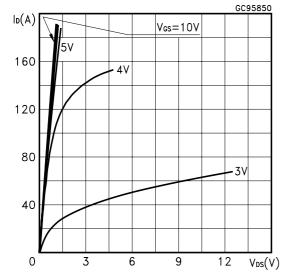


### Thermal Impedance

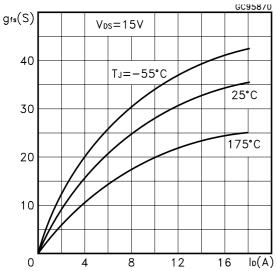


<sup>(5)</sup> Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %. (6)  $Q_{OSS} = C_{OSS}^* \Delta \ V_{in}$ ,  $C_{OSS} = C_{gd} + C_{ds}$ . See Appendix A (7) Gate charge for synchronous operation

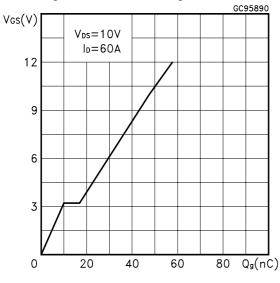
### **Output Characteristics**



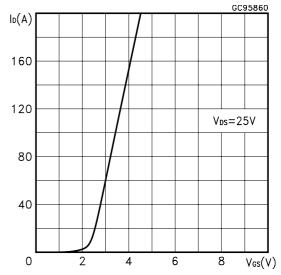
### Transconductance



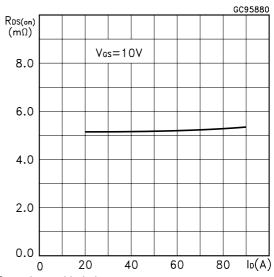
### Gate Charge vs Gate-source Voltage



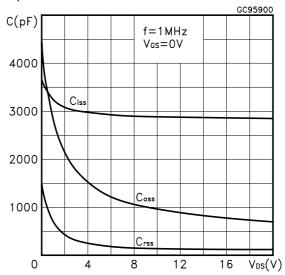
### **Transfer Characteristics**



### Static Drain-source On Resistance



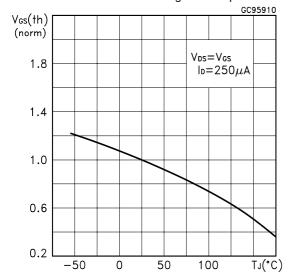
### Capacitance Variations



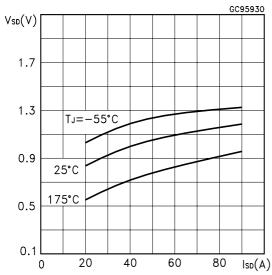
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### STD90NH02L

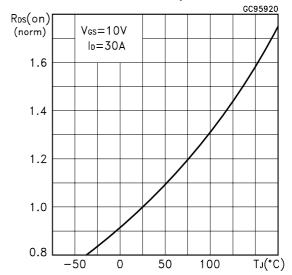
### Normalized Gate Threshold Voltage vs Temperature



### Source-drain Diode Forward Characteristics



### Normalized on Resistance vs Temperature



### Normalized Breakdown Voltage vs Temperature.

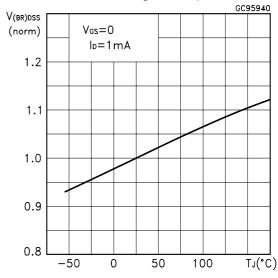


Fig. 1: Unclamped Inductive Load Test Circuit

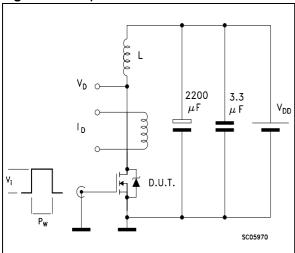
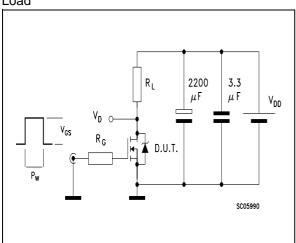


Fig. 3: Switching Times Test Circuits For Resistive Load



**Fig. 5:** Test Circuit For Inductive Load Switching And Diode Recovery Times

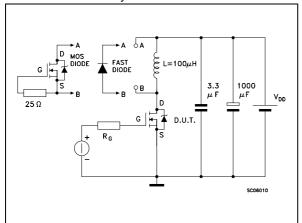


Fig. 2: Unclamped Inductive Waveform

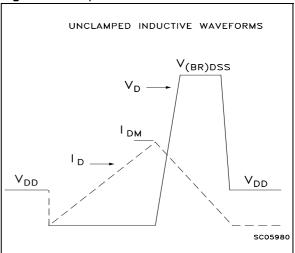
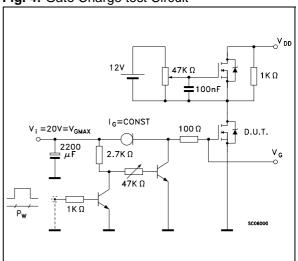
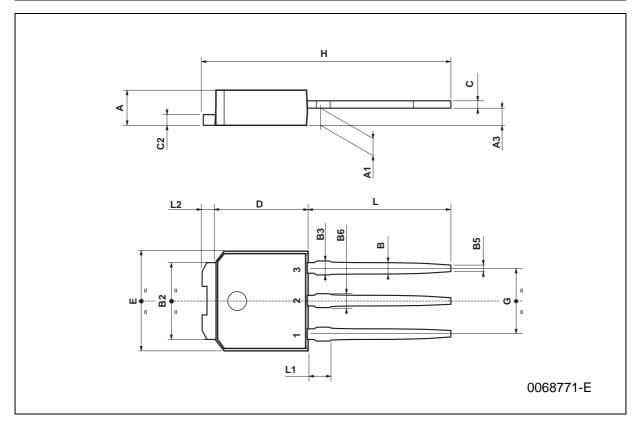


Fig. 4: Gate Charge test Circuit



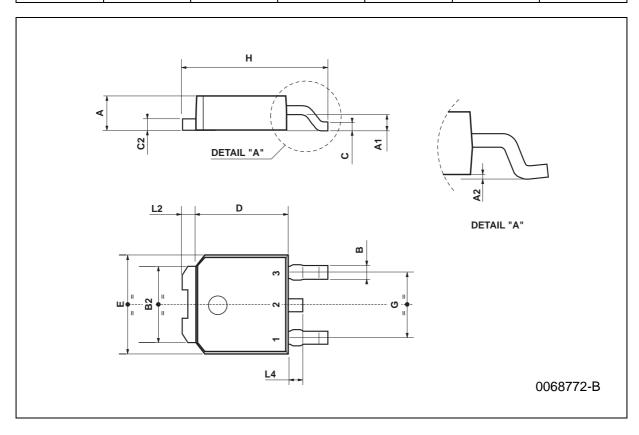
# TO-251 (IPAK) MECHANICAL DATA

DIM.		mm			inch	
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
В3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



# **TO-252 (DPAK) MECHANICAL DATA**

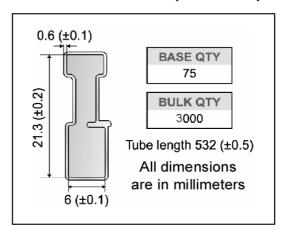
DIM.		mm			inch	
Divi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
B2	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
Е	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L2		0.8			0.031	
L4	0.6		1	0.023		0.039



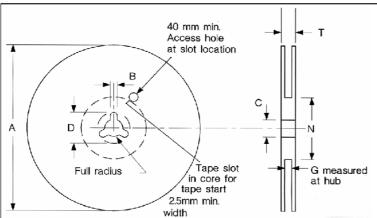
### **DPAK FOOTPRINT**

# 6.7 1.8 3.0 1.6 2.3 1.6 All dimensions are in millimeters

## **TUBE SHIPMENT (no suffix)\***



# TAPE AND REEL SHIPMENT (suffix "T4")\*

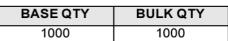


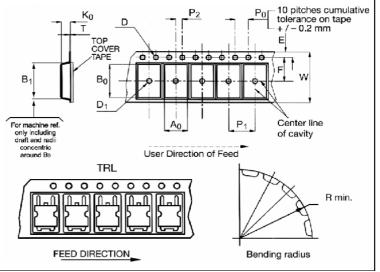
### **REEL MECHANICAL DATA**

DIM.	m	m	ine	ch
	MIN.	MAX.	MIN.	MAX.
Α		330		12.992
В	1.5		0.059	
С	12.8	13.2	0.504	0.520
D	20.2		0.795	
G	16.4	18.4	0.645	0.724
N	50		1.968	
Т		22.4		0.881

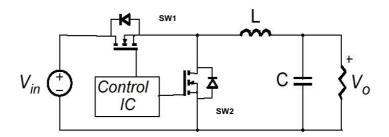
### TAPE MECHANICAL DATA

DIM.	mm		inch	
DIN.	MIN.	MAX.	MIN.	MAX.
A0	6.8	7	0.267	0.275
В0	10.4	10.6	0.409	0.417
B1		12.1		0.476
D	1.5	1.6	0.059	0.063
D1	1.5		0.059	
E	1.65	1.85	0.065	0.073
F	7.4	7.6	0.291	0.299
K0	2.55	2.75	0.100	0.108
P0	3.9	4.1	0.153	0.161
P1	7.9	8.1	0.311	0.319
P2	1.9	2.1	0.075	0.082
R	40		1.574	
W	15.7	16.3	0.618	0.641





# **APPENDIX A Buck Converter: Power Losses Estimation**



The power losses associated with the FETs in a Synchronous Buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is converted to allow for a safer working junction temperature.

The low side (SW2) device requires:

- ullet Very low  $R_{DS(on)}$  to reduce conduction losses
- ullet Small  $Q_{gls}$  to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Q<sub>rr</sub> to reduce losses on SW<sub>1</sub> during its turn-on
- The  $C_{gd}/C_{gs}$  ratio lower than  $V_{th}/V_{gg}$  ratio especially with low drain to source voltage to avoid the cross conduction phenomenon;

The high side (SW1) device requires:

- ullet Small  $R_g$  and  $L_s$  to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Q<sub>g</sub> to have a faster commutation and to reduce gate charge losses
- $\bullet \qquad \text{Low } R_{DS(on)} \text{ to reduce the conduction losses}.$

		High Side Switch (SW1)	Low Side Switch (SW2)
Pconducti	ion	$R_{DS(on)SW1} * I_L^2 * d$	$R_{DS(on)SW2} * I_L^2 * (1-d)$
Pswitchin	g	$V_{\text{in}} * (Q_{\text{gsth(SW1)}} + Q_{\text{gd(SW1)}}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
P <sub>diode</sub>	Recovery	Not Applicable	<sup>1</sup> V <sub>in</sub> *Q <sub>rr(SW2)</sub> * f
	Conduction	Not Applicable	$V_{\text{f(SW2)}} * I_{\text{L}} * t_{\text{deadtime}} * f$
$P_{\text{gate}(Q_G)}$	)	$Q_{g(SW1)}*V_{gg}*f$	$Q_{gls(SW2)}*V_{gg}*f$
P <sub>Qoss</sub>		$\frac{\underline{V_{in}} * Q_{oss(SW1)} * f}{2}$	$\frac{V_{\text{in}} * Q_{\text{oss(SW2)}} * f}{2}$

Parameter	Meaning	
d	Duty-cycle	
Qgsth	Post threshold gate charge	
$Q_{ m gls}$	Third quadrant gate charge	
Pconduction	On state losses	
Pswitching	On-off transition losses	
Pdiode	Conduction and reverse recovery diode losses	
Pgate	Gate drive losses	
P <sub>Qoss</sub>	Output capacitance losses	

<sup>&</sup>lt;sup>1</sup> Dissipated by SW1 during turn-on

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